## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Examiner | Art Unit | Page 1 of 1 | U.S. PATENT DOCUMENTS \* | Document Number | Date | Country Code-Number-Kind Code | MM-YYYYY | Name | Classification | Classification | Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Page 1 of 1 | Classification | Classification | Classification | Classification | Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Page 1 of 1 | Classification | Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Page 1 of 1 | Classification | Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Page 1 of 1 | Classification | Control No. | Applicant(s)/Patent Under Reexamination | EPSTEIN, MICHAEL A. | Page 1 of 1 | Control No. | Contro

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,857,021	01-1999	Kataoka et al.	705/54
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## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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